

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE)
CB SCHEME

CB TEST CERTIFICATE

Product	Intel® NUC
Name and address of the applicant	INTEL CORPORATION 2200 Mission College Blvd Santa Clara, CA 95054 USA
Name and address of the manufacturer	INTEL CORPORATION 2200 Mission College Blvd Santa Clara, CA 95054 USA
Name and address of the factory	MAINTEK COMPUTER (SUZHOU) CO LTD 233 JIN FENG RD NEW DISTRICT SUZHOU JIANGSU 215011 CHINA
Note: When more than one factory, please report on page 2	<input type="checkbox"/> Additional Information on page 2
Ratings and principal characteristics	19Vdc, 4.74A
Trademark (if any)	INTEL 
Type of Customer's Testing Facility (CTF) Stage used	
Model / Type Ref.	NUC8IN, xNUC8xINx (where x can be a combination of alphanumeric characters or blank)
Additional information (if necessary may also be reported on page 2)	Additionally evaluated to EN 62368-1:2014 / A11: 2017 National Difference specified in the CB Test Report <input type="checkbox"/> Additional Information on page 2
A sample of the product was tested and found to be in conformity with	IEC 62368-1:2014
As shown in the Test Report Ref. No. which forms part of this Certificate	ASL18110532 issued on 2019-01-09

This CB Test Certificate is issued by the National Certification Body



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
 UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
 UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
 UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2019-01-14

Signature:

Jan-Erik Storgaard